



MICROCHIP

QUALIFICATION PLAN SUMMARY

PCN #: BLAS-09BCAQ410

Date:

February 12, 2026

Qualification of MMT as a new final test site and MTAI as a new scan and pack site for SG2524N, SG3524D and SG3524D-TR catalog part numbers (CPN) available in 16L SOIC (.150in) package and 16L PDIP (.300in) package.

Purpose: Qualification of MMT as a new final test site and MTAI as a new scan and pack site for SG2524N, SG3524D and SG3524D-TR catalog part numbers (CPN) available in 16L SOIC (.150in) package and 16L PDIP (.300in) package.

CCB No.: 8030.001

Test Name	Test Conditions	Sample Size	Qty of Lots	Fail/Accept Criteria
Bin and Yield Comparison	Test the same units at existing and destination locations and compare Bin and Yield data.	33	1	≤0.1%
Parametric / Characterization Comparison	Characterize the same units at existing and destination locations and compare data.	33	1	≤10.0%
Correlation Lot Report	Yield at each step and reject analysis between systems. 33 units are tested as lot correlation.	33	1	≤0.1%